Supplementary Materials

In-situ synchrotron X-ray micro-diffraction investigation of elastic strains in laminated Ti-Al composites

Tianbo Yu [1,*], Yan Du [2], Guohua Fan [3], Rozaliya Barabash [4], Dorte Juul Jensen [1], Yubin Zhang [1]

[1] Department of Mechanical Engineering, Technical University of Denmark, DK-2800 Kgs. Lyngby, Denmark; tiyu@mek.dtu.dk
[2] Northwest Institute for Nonferrous Metal Research, Xi'an 710016, PR China; ydu_mail@163.com
[3] Key Laboratory for Light-weight Materials, Nanjing Tech University, Nanjing 211816, PR China; ghfan@njtech.edu.cn
[4] The University of Tennessee, Knoxville, TN 37996, USA; rbarabas@utk.edu
* Correspondence: tiyu@mek.dtu.dk

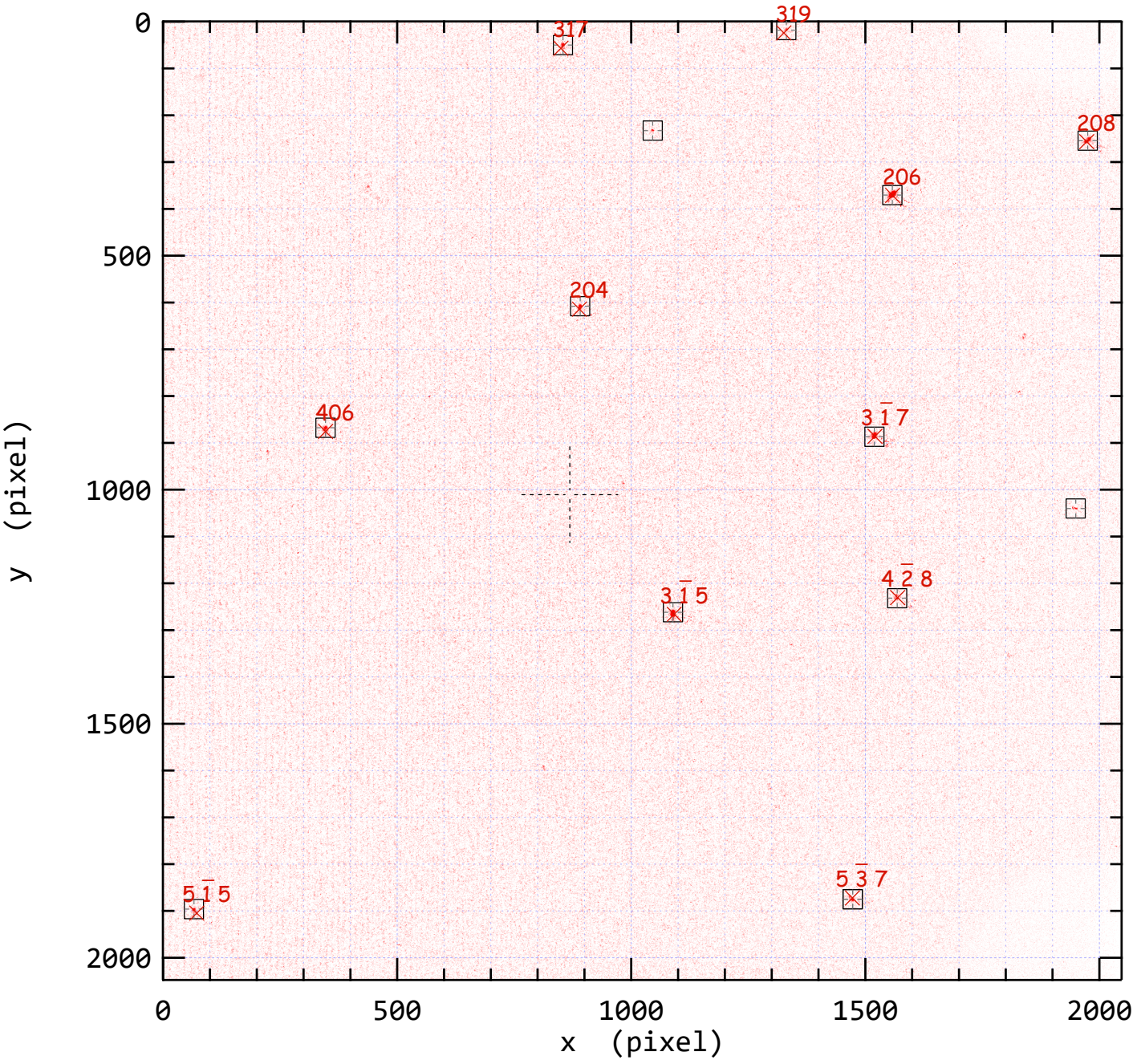

Figure S1. Example of depth-resolved diffraction pattern from the Al layer before tensile loading.

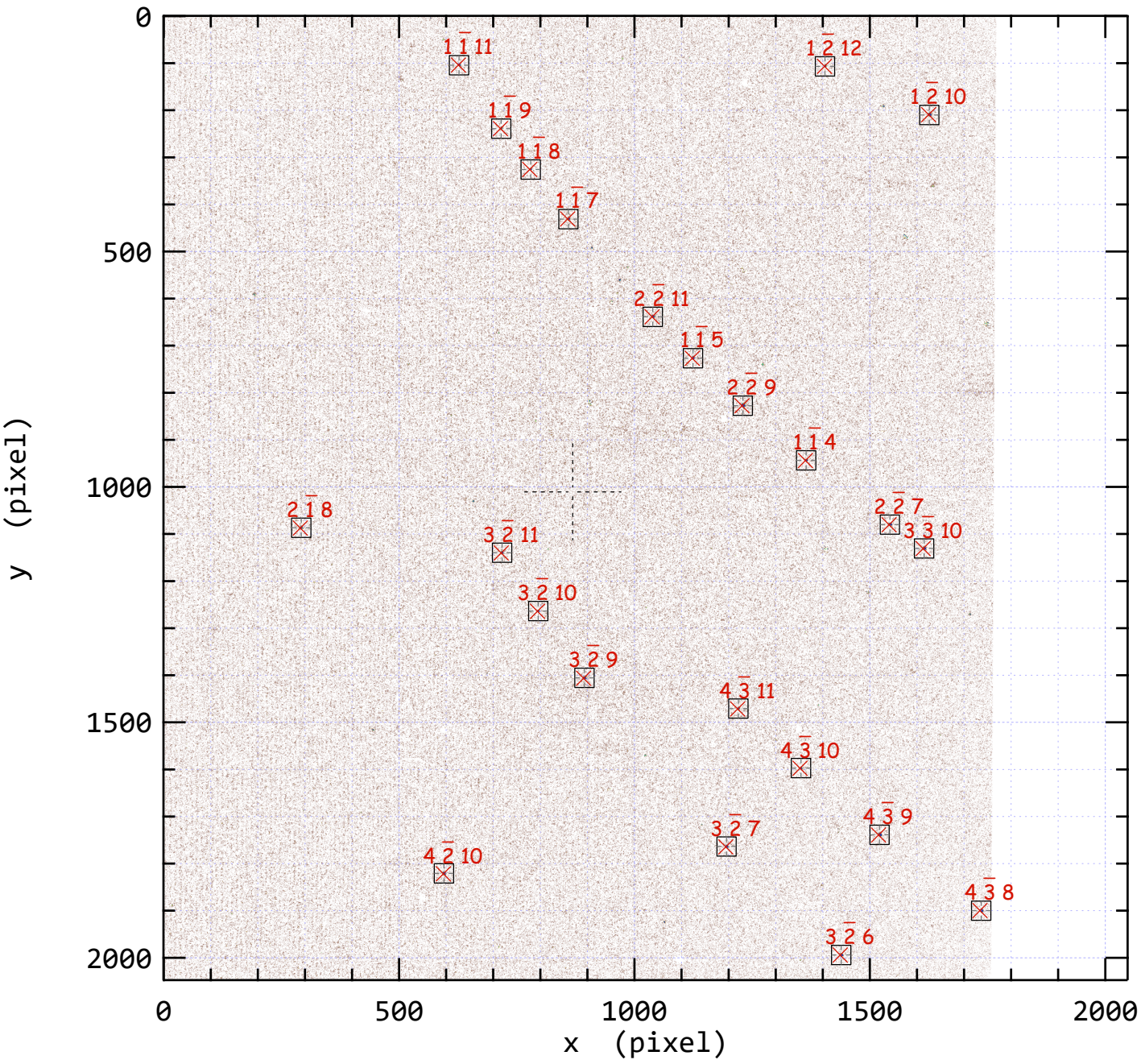

Figure S2. Example of depth-resolved diffraction pattern from an Ti grain below the Al layer before tensile loading.

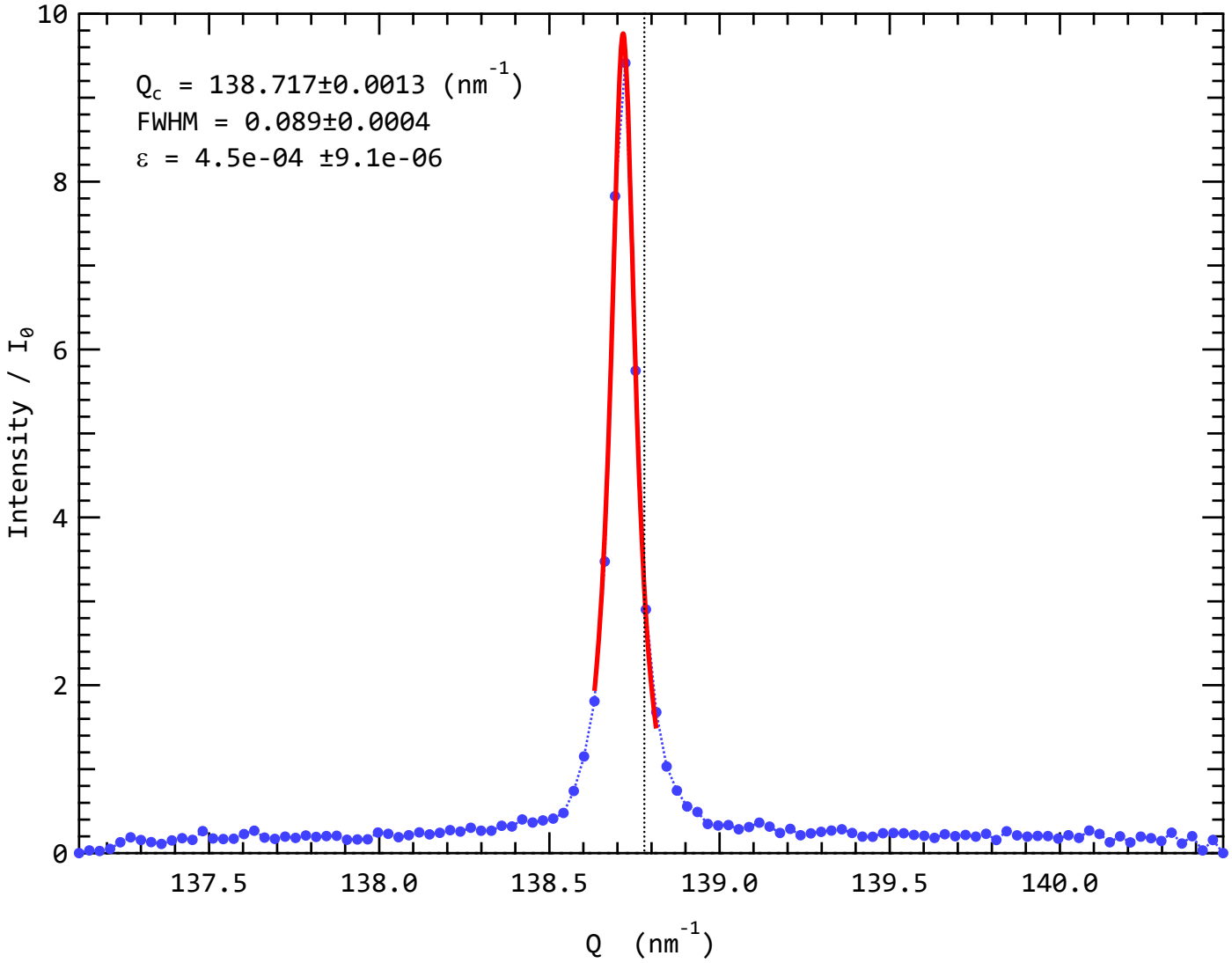

Figure S3. Example of diffraction intensity profile (fitted by a Gaussian function) of the energy scan in an Al voxel before tensile loading.

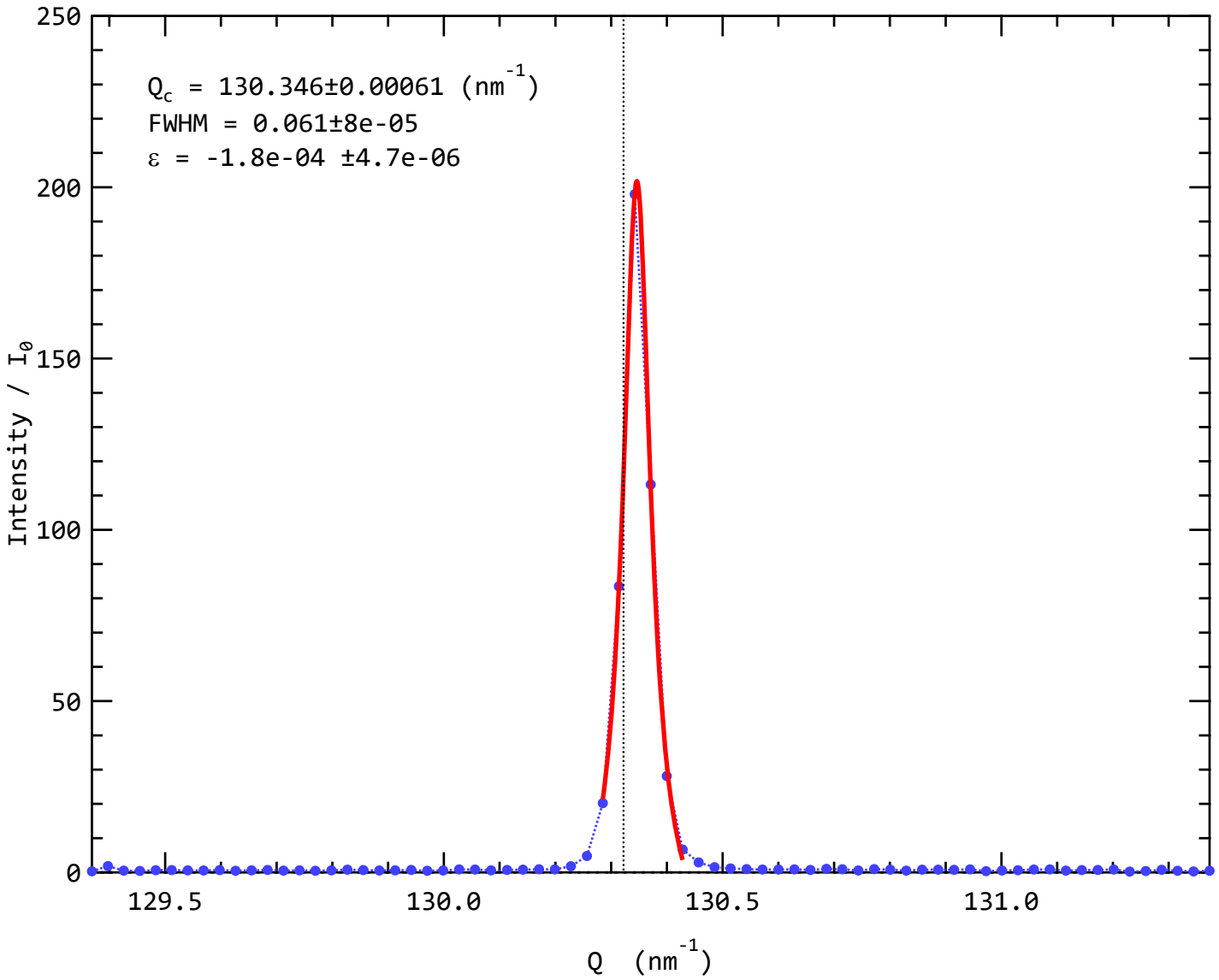

Figure S4. Example of diffraction intensity profile (fitted by a Gaussian function) of the energy scan in a Ti voxel before tensile loading.